

APR 29 2005

Sheet 1 of 1

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05542-552001	Application No. 10/732,966
	Applicant Chen et al.		
	Filing Date December 10, 2003	Group Art Unit 1763	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
dy	AA	5,906,532	05/25/1999	Nakajima et al.			
dy	AB	2004/0152403 A1	08/05/2004	Marohl et al.			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
dy	AC	WO2004/033152 A1	04/2004	WIPO				
dy	AD	WO 02/098608 A1	12/2002	WIPO				
dy	AE	DE 203 09 051 U1	11/2003	DE			English Abstract U.S. Equivalent 2004/0152403-A1	

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
dy	AF	International Search Report, International Application Serial No. PCT/US2004/041322, April 18, 2005, 4 pp.

Examiner Signature

Date Considered


EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Disclosure Form (PTO-1449)

Information Disclosure Statement by Applicant (Use several sheets if necessary)		Chen et al.	
		Filing Date December 10, 2003	Group Art Unit Unknown
(37 CFR §1.98(b))			

U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
dy	AA	5,205,082	04/27/93	Shendon et al.			
dy	AB	5,423,558	06/13/95	Koeth et al.			
dy	AC	5,584,751	12/17/96	Kobayashi et al.			
dy	AD	5,605,487	02/25/87	Hileman et al.			
dy	AE	5,605,488	02/25/97	Ohashi et al.			
dy	AF	5,635,083	06/03/97	Breivogel et al.			
dy	AG	5,643,053	07/01/97	Shendon			
dy	AH	5,643,061	07/01/97	Jackson et al.			
dy	AI	5,645,474	07/08/97	Kubo et al.			
dy	AJ	5,647,789	07/15/97	Kitta et al.			
dy	AK	5,664,988	09/09/97	Stroupe et al.			
dy	AL	5,695,392	12/09/97	Kim			
dy	AM	5,759,918	06/02/98	Hoshizaki et al.			
dy	AN	5,762,544	06/98/98	Zuniga et al.			
dy	AO	5,851,140	12/22/98	Barns et al.			
dy	AP	6,068,548	05/2000	Vote et al.			
dy	AQ	6,183,354	02/2001	Zuniga et al.			
dy	AR	6,244,932	06/2001	Govzman et al.			
dy	AS	6,251,215	06/26/01	Zuniga et al.			
dy	AT	6,277,008	08/21/01	Masuta et al.			

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No
dy	AU	0 988 931 A2	03/29/00	EPO			
dy	AV	0 790 100 A1	08/20/97	EPO			
dy	AW	0 841 123 A1	05/13/98	EPO			
dy	AX	0 776 730 A	06/04/97	EPO			

Examiner Signature 	Date Considered 11/11/2003
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Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AY	2 336 121 A	10/13/99	Great Britain				

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AZ	"SPM's PPS Ring Sales History", January 1997 thru November 1999
	AAA	Yuan, et al., A novel Wafer Carrier Ring Design Minimizes Edge Over-Polishing Effects for Chemical Mechanical Polishing, June 27-29 1995 VMIC Conference, 1995 ISMIC 104/95/525, pp. 525-527.

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